

March 2013

## **FDD050N03B**

# N-Channel PowerTrench<sup>®</sup> MOSFET 30 V, 90 A, 5.0 m $\Omega$

#### **Features**

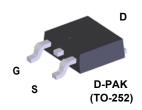
- $R_{DS(on)}$  = 3.7 m $\Omega$  ( Typ.)@  $V_{GS}$  = 10 V,  $I_D$  = 25 A
- · Fast Switching Speed
- Low Gate Charge, Q<sub>G</sub> = 33 nC( Typ.)
- High Performance Trench Technology for Extremely Low  $R_{DS(on)}$
- · High Power and Current Handling Capability
- · RoHS Compliant

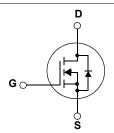
## **Description**

This N-Channel MOSFET is produced using Fairchild Semiconductor  $^{\!8}\!\!$  's advance PowerTrench  $^{\!8}\!\!$  process that has been tailored to minimize the on-state resistance while maintaining superior switching performance.

## **Applications**

• Synchronous Rectification for ATX / Server / Telecom PSU





## **MOSFET Maximum Ratings** $T_C = 25^{\circ}C$ unless otherwise noted

Symbol		Parameter		FDD050N03B	Unit
V <sub>DSS</sub>	Drain to Source Voltage			30	V
V <sub>GSS</sub>	Gate to Source Voltage			±16	V
		- Continuous (T <sub>C</sub> = 25°C, Silico	on Limited)	90*	
I <sub>D</sub>	Drain Current	- Continuous (T <sub>C</sub> = 100°C, Silic	con Limited)	63*	Α
		- Continuous (T <sub>C</sub> = 25°C, Pack	age Limited)	50	
I <sub>DM</sub>	Drain Current	- Pulsed	(Note 1)	360	Α
E <sub>AS</sub>	Single Pulsed Avalanche Energy (Note 2)			72	mJ
dv/dt	Peak Diode Recovery dv/dt (Note 3)		(Note 3)	2	V/ns
n	Dawer Dissipation	(T <sub>C</sub> = 25°C)		65	W
$P_{D}$	Power Dissipation	- Derate above 25°C		0.43	W/°C
T <sub>J</sub> , T <sub>STG</sub>	Operating and Storage Temperature Range			-55 to +175	°C
T <sub>L</sub>	Maximum Lead Temperature for Soldering Purpose, 1/8" from Case for 5 Seconds			300	°C

\*Calculated continuous current based on maximum allowable junction temperature. Package limitation current is 50A.

#### **Thermal Characteristics**

Symbol	Parameter	FDD050N03B	Unit
$R_{\theta JC}$	Thermal Resistance, Junction to Case, Max.	2.3	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient, Max. (Note 5)	40	°C/VV

## **Package Marking and Ordering Information**

Device Marking	Device	Package	Reel Size	Tape Width	Quantity
FDD050N03B	FDD050N03B	D-PAK	330mm	16mm	2500

## **Electrical Characteristics** $T_C = 25^{\circ}C$ unless otherwise noted

Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Unit
Off Charac	eteristics					
BV <sub>DSS</sub>	Drain to Source Breakdown Voltage	$I_D = 250 \mu A$ , $V_{GS} = 0 V$ , $T_C = 25 ^{\circ} C$	30	-	-	V
$\frac{\Delta BV_{DSS}}{\Delta T_{J}}$	Breakdown Voltage Temperature Coefficient	I <sub>D</sub> = 250μA, Referenced to 25°C	-	13	-	mV/°C
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	V <sub>DS</sub> = 24V, V <sub>GS</sub> = 0V	-	-	1	μА
I <sub>GSS</sub>	Gate to Body Leakage Current	$V_{GS} = \pm 16V, V_{DS} = 0V$	-	-	±100	nA

#### On Characteristics

V <sub>GS(th)</sub>	Gate Threshold Voltage	$V_{GS} = V_{DS}, I_{D} = 250 \mu A$	1.25	2.0	3.0	V
D	Static Drain to Source On Resistance	$V_{GS} = 10V, I_D = 25A$	-	3.7	5.0	mΩ
R <sub>DS(on)</sub> Static Drain to Source On Resistance	Static Drain to Source On Resistance	V <sub>GS</sub> = 4.5V, I <sub>D</sub> = 15A	-	5.2	8.1	1115.2
9 <sub>FS</sub>	Forward Transconductance	$V_{DS} = 5V, I_{D} = 50A$	-	169	-	S

#### **Dynamic Characteristics**

C <sub>iss</sub>	Input Capacitance	V 45V V 0V		-	2160	2875	pF
Coss	Output Capacitance	V <sub>DS</sub> = 15V, V <sub>GS</sub> = 0V f = 1MHz		-	805	1070	pF
C <sub>rss</sub>	Reverse Transfer Capacitance	1 - 111112		-	85	130	pF
Q <sub>g(tot)</sub>	Total Gate Charge at 10V	V <sub>DD</sub> = 15V, I <sub>D</sub> = 50A		-	33	43	nC
$Q_{gs}$	Gate to Source Gate Charge	V <sub>GS</sub> = 10V		-	7.8	-	nC
Q <sub>gs2</sub>	Gate Charge Threshold to Plateau			-	3.8	-	nC
Q <sub>qd</sub>	Gate to Drain "Miller" Charge		(Note 4)	-	4.6	-	nC

### **Switching Characteristics**

t <sub>d(on)</sub>	Turn-On Delay Time	V <sub>DD</sub> = 15V, I <sub>D</sub> = 50A		-	14.5	39	ns
t <sub>r</sub>	Turn-On Rise Time	$V_{GS} = 10V, R_{GEN} = 4.7\Omega$		-	4.5	18	ns
t <sub>d(off)</sub>	Turn-Off Delay Time			-	30	70	ns
t <sub>f</sub>	Turn-Off Fall Time	(Not	e 4)	-	4.5	19	ns

#### **Drain-Source Diode Characteristics**

$I_S$	Maximum Continuous Drain to Source Diode Forward Current		-	-	90*	Α
I <sub>SM</sub>	Maximum Pulsed Drain to Source Diode Forward Current		-	-	360	Α
$V_{SD}$	Drain to Source Diode Forward Voltage V <sub>GS</sub> = 0V, I <sub>SD</sub> = 50A		-	-	1.3	V
t <sub>rr</sub>	Reverse Recovery Time	V <sub>GS</sub> = 0V, I <sub>SD</sub> = 50A	-	33	-	ns
Q <sub>rr</sub>	Reverse Recovery Charge dI <sub>F</sub> /dt = 100A/μs		-	19	-	nC

#### Notes:

- Repetitive Rating: Pulse width limited by maximum junction temperature
- 2. L = 1mH, I<sub>AS</sub> = 12A, V<sub>DD</sub> = 27V, R<sub>G</sub> = 25 $\Omega$ , Starting T<sub>J</sub> = 25 $^{\circ}$ C
- 3. I\_{SD}  $\leq$  50A, di/dt  $\leq$  200A/µs, V\_{DD}  $\leq$  BV\_DSS, Starting T\_J = 25°C
- 4. Essentially Independent of Operating Temperature Typical Characteristics
- 5. When mounted on a 1 in<sup>2</sup> pad of 2 oz copper

## **Typical Performance Characteristics**

Figure 1. On-Region Characteristics

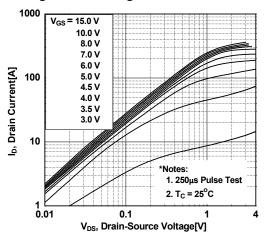


Figure 3. On-Resistance Variation vs.
Drain Current and Gate Voltage

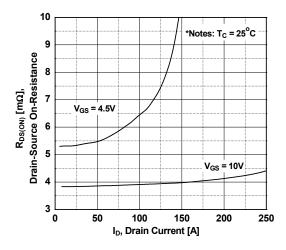


Figure 5. Capacitance Characteristics

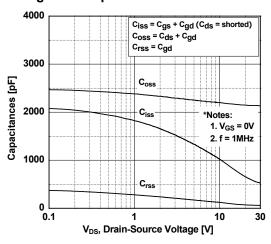


Figure 2. Transfer Characteristics

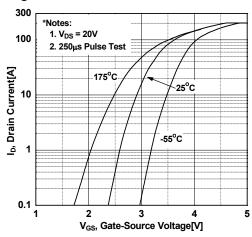


Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperature

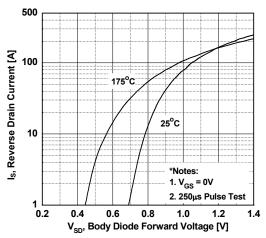
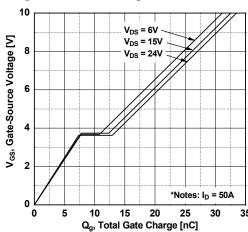


Figure 6. Gate Charge Characteristics



## **Typical Performance Characteristics** (Continued)

Figure 7. Breakdown Voltage Variation vs. Temperature

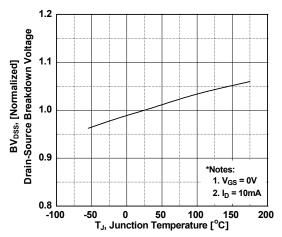


Figure 9. Maximum Safe Operating Area

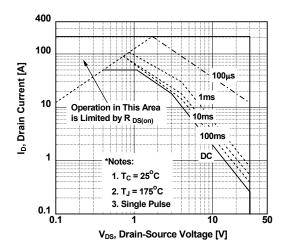


Figure 8. On-Resistance Variation vs. Temperature

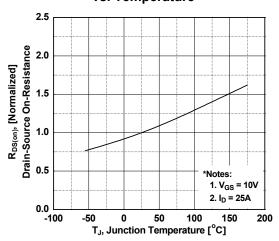


Figure 10. Maximum Drain Current vs. Case Temperature

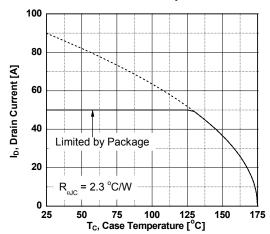
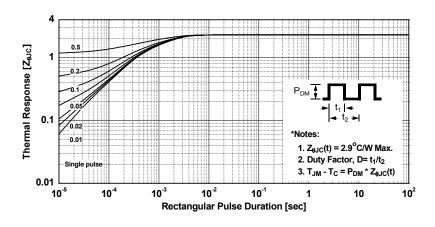
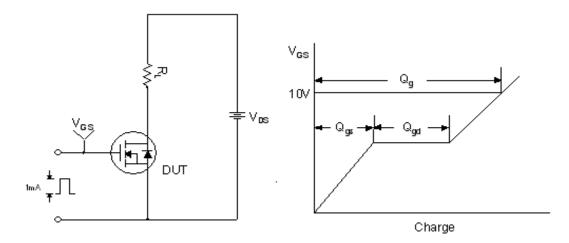


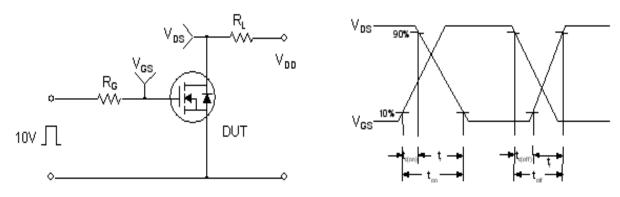
Figure 11. Transient Thermal Response Curve



#### **Gate Charge Test Circuit & Waveform**

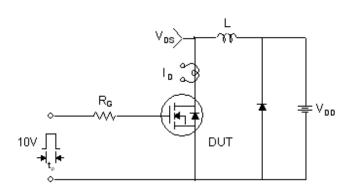


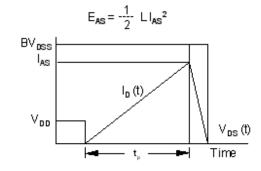
#### **Resistive Switching Test Circuit & Waveforms**



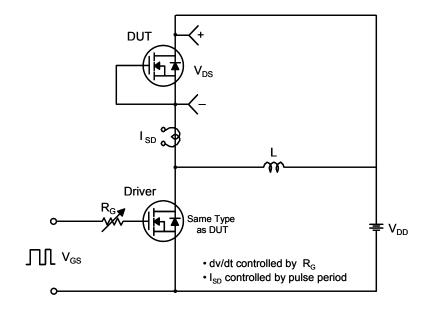
**Unclamped Inductive Switching Test Circuit & Waveforms** 

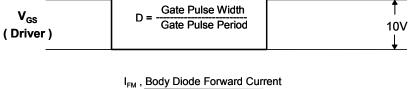
5

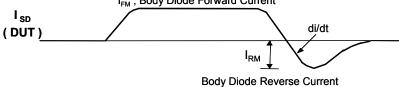


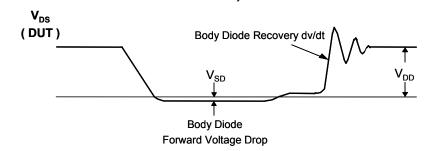


#### Peak Diode Recovery dv/dt Test Circuit & Waveforms



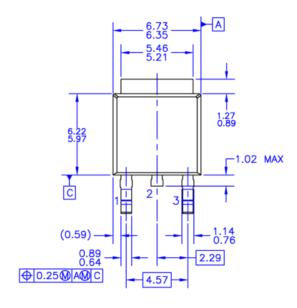


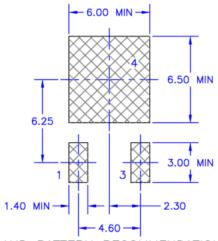




#### **Mechanical Dimensions**

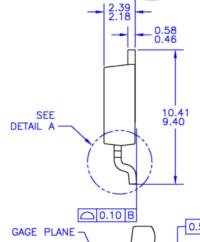
## **D-PAK**





4.32 MIN NOTE D 5.21 MIN







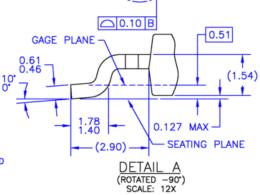
- NOTES: UNLESS OTHERWISE SPECIFIED

  A) THIS PACKAGE CONFORMS TO JEDEC, TO-252, ISSUE C, VARIATION AA.

  B) ALL DIMENSIONS ARE IN MILLIMETERS.

  - c)

  - DIMENSIONING AND TOLERANCING PER
    ASME Y14.5M-1994.
    HEAT SINK TOP EDGE COULD BE IN CHAMFERED
    CORNERS OR EDGE PROTRUSION.
    PRESENCE OF TRIMMED CENTER LEAD D)
  - E)
  - F)
  - PRESENCE OF TRIMMED CENTER LEAD
    IS OPTIONAL.
    DIMENSIONS ARE EXCLUSSIVE OF BURSS,
    MOLD FLASH AND TIE BAR EXTRUSIONS.
    LAND PATTERN RECOMENDATION IS BASED ON IPC7351A STD
    T0220P1003X238-3N.
    DRAWING NUMBER AND REVISION: MKT-T0252A03REV8



**Dimensions in Millimeters** 





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